


<b>Search Notes</b>  	<b>Application/Control No.</b>  10624524	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Tran, Nhan T	<b>Art Unit</b>  2622

SEARCHED			
Class	Subclass	Date	Examiner
348	333.06	11/1/2006	NT
348	373-376	10/4/2007	NT
455	575.3	4/8/2008	NT

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (USPAT, PG PUB, JPO, EPO, DERWENT, IBM_TDB)	10/4/2007	NT
Updated text search (please see all previous search notes)	4/8/2008	NT
Inventorship search - see previous search	4/8/2008	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
ALL	PG PUB text search - see search history	4/8/2008	NT